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| Notice of References Cited | Application/Control No. 10/807,555 | Applicant(s)/Patent Under Reexamination KEANE ET AL. | |
| | Examiner Filip Zec | Art Unit 3744 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------------|----------------|
| | A | US-6,196,998 | 03-2001 | Jansen et al. | 604/111 |
| | B | US-6,632,199 | 10-2003 | Tucker et al. | 604/192 |
| | C | US-6,027,482 | 02-2000 | Imbert, Claude | 604/256 |
| | D | US-6,206,861 | 03-2001 | Mayer, Bruno Franz P. | 604/246 |
| | E | US-4,667,837 | 05-1987 | Vitello et al. | 215/228 |
| | F | US-6,394,983 | 05-2002 | Mayoral et al. | 604/192 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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